



1M x32 FLASH SIM M

PRELIMINARY*

FEATURES

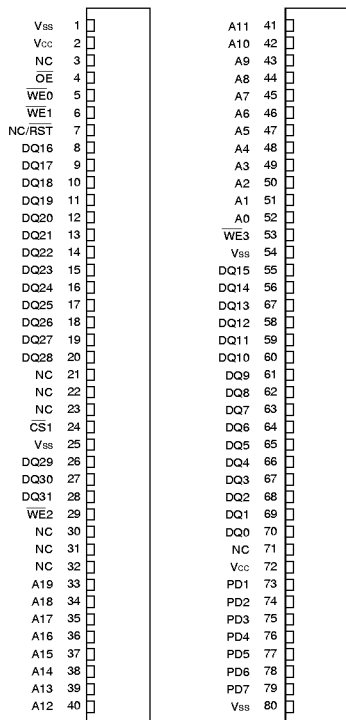
- Access Time of 90ns
- Packaging:
 - 80 pin SIMM
 - 80 pin SIMM, Low profile **
 - The module is manufactured with four 1Mx8 CMOS flash memory devices in TSOP on a laminate substrate.
- JEDEC standard
- Reset control options:
 - $\overline{\text{RESET}}$ tied to Vcc
 - $\overline{\text{RESET}}$ tied to pin 7 for system control of reset
 - $\overline{\text{RESET}}$ tied to Power Supervisor Circuit.
- Sector Architecture
 - 16 equal size sectors of 64KBytes per each 1M x8 chip
 - Two step sequence of erase ensures that memory contents are not accidentally erased.
- AMD Part Number Am29F080-90 Flash Memory Components

- 100,000 Erase/ Program Cycles
- Organized as 1M x32
- Commercial Temperature Range
- 5 Volt Programming. $5V \pm 10\%$ Supply.
- Low Power CMOS (0 - 70°C)
- Built-in Decoupling Caps and Multiple Ground Pins for Low Noise Operation, Separate Power and Ground Planes to improve noise immunity
- Standard Programming Algorithms for AMD Am29F080 Flash

* This data sheet describes a product under development, not fully characterized, and is subject to change without notice.

** Package to be developed.

FIG. 1 PIN CONFIGURATION FOR WPF1M32X-90XC5



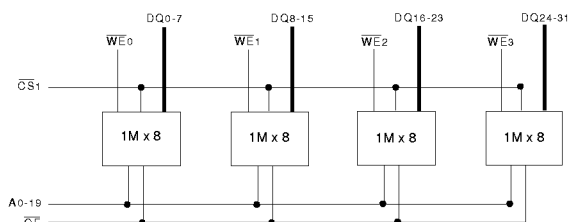
PIN DESCRIPTION

DQ0-31	Data Inputs/Outputs
A0-19	Address Inputs
$\overline{\text{WE}}0-3$	Write Enables
$\overline{\text{CS}}1$	Chip Enable
$\overline{\text{OE}}$	Output Enable
$\overline{\text{RST}}$	Reset (optional)
Vcc	Power Supply
Vss	Ground
PD1-7	Presence Detects
NC	No Connect

Presence Detect

Speed	PD1	PD2	PD3	PD4	PD5	PD6	PD7
90ns	1	0	1	0	1	1	0
0: GND 1: Open							

BLOCK DIAGRAM





ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ratings	Unit
Voltage on Any Pin Relative to Vss (except Vcc)	V _T	-2.0 to +7.0	V
Power Dissipation	P _T	1.32	W
Operating Temperature	T _A	0 to +70	°C
Storage Temperature	T _{stg}	-65 to +125	°C
Short Circuit Output Current	I _{os}	200	mA

CAPACITANCE

(T_A = +25°C)

Parameter	Symbol	Conditions	Max	Unit
$\overline{OE}$ capacitance	C _{OE}	V _{IN} = 0 V, f = 1.0 MHz	60	pF
$\overline{WE}$ capacitance	C _{WE}	V _{IN} = 0 V, f = 1.0 MHz	20	pF
$\overline{CS}$ capacitance	C _{CS}	V _{IN} = 0 V, f = 1.0 MHz	50	pF
Data I/O capacitance	C _{I/O}	V _{I/O} = 0 V, f = 1.0 MHz	18	pF
Address input capacitance	C _{AD}	V _{IN} = 0 V, f = 1.0 MHz	60	pF

This parameter is guaranteed by design but not tested.

RECOMMENDED DC OPERATING CONDITIONS

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	V _{CC}	4.5	5.0	5.5	V
Ground	V _{SS}	0	0	0	V
Input High Voltage	V _{IH}	0.7 x V _{CC}	-	V _{CC} + 0.3	V
Input Low Voltage	V _{IL}	-0.5	-	+0.8	V
Voltage for Autoselect and Sector Unprotect	V _{ID}	11.5	-	12.5	V

DC CHARACTERISTICS - CMOS COMPATIBLE

(V_{CC} = 5.0V, V_{SS} = 0V, T_A = 0°C to +70°C)

Parameter	Symbol	Conditions	Min	Max	Unit
Input Leakage Current	I _{LI}	V _{CC} = 5.5, V _{IN} = V _{SS} or V _{CC}		10	μA
Output Leakage Current	I _{LO}	V _{CC} = 5.5, V _{IN} = V _{SS} or V _{CC}		10	μA
V _{CC} Active Current for Read (1)	I _{CC1}	$\overline{CS}$ = V _{IL} , $\overline{OE}$ = V _{IH} , f = 5MHz		120	mA
V _{CC} Active Current for Program or Erase (2)	I _{CC2}	$\overline{CS}$ = V _{IL} , $\overline{OE}$ = V _{IH}		240	mA
V _{CC} Standby Current	I _{CC4}	V _{CC} = 5.5, $\overline{CS}$ = V _{IH} , f = 5MHz		1.0	mA
V _{CC} Static Current	I _{CC3}	V _{CC} = 5.5, $\overline{CS}$ = V _{IH}		20	μA
Output Low Voltage	V _{OL}	I _{OL} = 12.0 mA, V _{CC} = 4.5		0.45	V
Output High Voltage	V _{OH1}	I _{OH} = -2.5 mA, V _{CC} = 4.5	0.85 x V _{CC}		V
Low V _{CC} Lock-Out Voltage	V _{LKO}		3.2	4.2	V

NOTES:

1. The I_{CC} current listed includes both the DC operating current and the frequency dependent component (at 5 MHz). The frequency component typically is less than 2 mA/MHz, with $\overline{OE}$ at V_{IH}.
2. I_{CC} active while Embedded Algorithm (program or erase) is in progress.
3. DC test conditions: V_{IL} = 0.3V, V_{IH} = V_{CC} - 0.3V

**AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS, $\overline{WE}$ CONTROLLED**(V_{CC} = 5.0V, T_A = 0°C to +70°C)

Parameter	Symbol		-90		Unit
			Min	Max	
Write Cycle Time	t _{AVAV}	t _{WC}	90		ns
Chip Select Setup Time	t _{ELWL}	t _{CS}	0		ns
Write Enable Pulse Width	t _{WLWH}	t _{WP}	45		ns
Address Setup Time	t _{AVWH}	t _{AS}	0		ns
Data Setup Time	t _{DVWH}	t _{DS}	45		ns
Data Hold Time	t _{WHDX}	t _{DH}	0		ns
Address Hold Time	t _{WHAX}	t _{AH}	45		ns
Write Enable Pulse Width High	t _{WHWL}	t _{WPH}	20		ns
Duration of Byte Programming Operation	t _{WHWH1}			1.0	ms
Sector Erase Time	t _{WHWH2}			15	sec
Read Recovery Time before Write	t _{GHWL}		0		μs
V _{CC} Set-up Time	t _{VCS}		50		μs
Chip Programming Time				50	sec
Output Enable Setup Time		t _{OES}	0		ns
Output Enable Hold Time (1)		t _{OEH}	10		ns
Chip Erase Time				240	sec
$\overline{RESET}$ Pulse Width (2)		t _{RP}	500		ns

1. For Toggle and Data Polling.

2. Reset optional.

AC CHARACTERISTICS – READ ONLY OPERATIONS(V_{CC} = 5.0V, T_A = 0°C to +70°C)

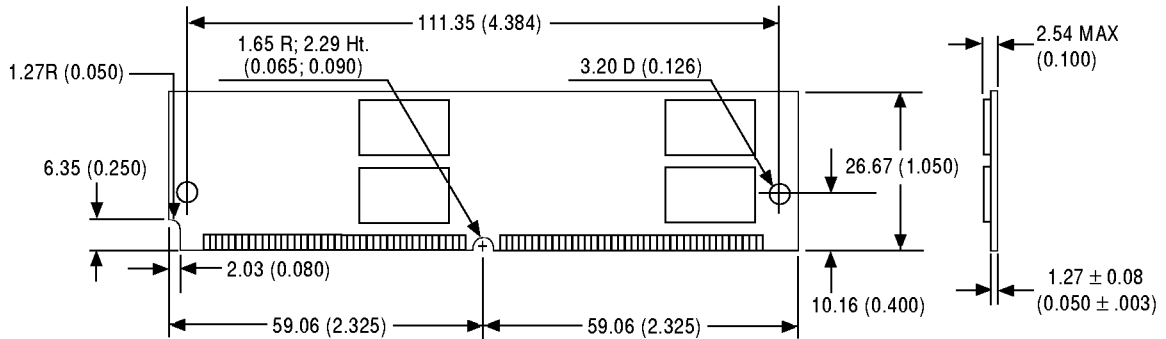
Parameter	Symbol		-90		Unit
			Min	Max	
Read Cycle Time	t _{AVAV}	t _{RC}	90		ns
Address Access Time	t _{AVOV}	t _{ACC}		90	ns
Chip Select Access Time	t _{ELOV}	t _{CE}		90	ns
Output Enable to Output Valid	t _{GLOV}	t _{OE}		40	ns
Chip Select to Output High Z (1)	t _{EHQZ}	t _{DF}		20	ns
Output Enable High to Output High Z (1)	t _{GHQZ}	t _{DF}		20	ns
Output Hold from Address, CS or OE Change, whichever is First	t _{AXQX}	t _{OH}	0		ns
$\overline{RST}$ Low to Read Mode (1) (2)		t _{Ready}		20	μs

1. Guaranteed by design, but not tested.

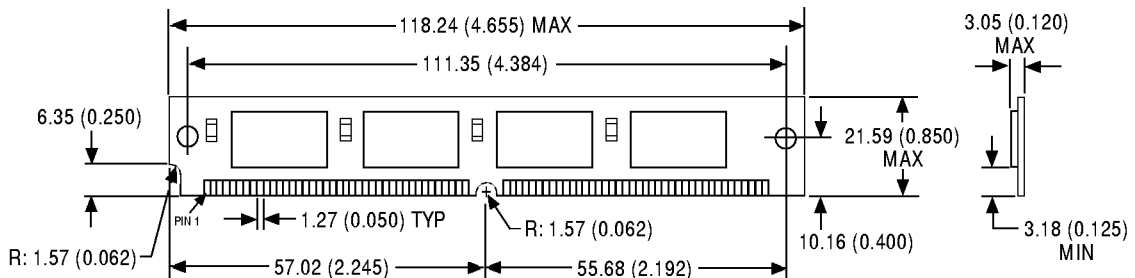
2. Reset optional.

**AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS, $\overline{CS}$ CONTROLLED**
($V_{CC} = 5.0V$, $V_{SS} = 0V$, $T_A = 0^{\circ}C$ to $+70^{\circ}C$)

Parameter	Symbol		-90		Unit
			Min	Max	
Write Cycle Time	tAVAV	twc	90		ns
Write Enable Setup Time	twLEL	twS	0		ns
Chip Select Pulse Width	tELEH	tCP	45		ns
Address Setup Time	tAVEL	tAS	0		ns
Data Setup Time	tdVEH	tdS	45		ns
Data Hold Time	tEHDX	tdH	0		ns
Address Hold Time	tELAX	tAH	45		ns
Chip Select Pulse Width High	tEHEL	tCPH	20		ns
Duration of Byte Programming Operation	twHWH1			1.0	ms
Sector Erase Time	twHWH2			15	sec
Read Recovery Time	tGHEL		0		μ s
Chip Programming Time				50	sec
Chip Erase Time				240	sec

**PACKAGE DIMENSION: 80-PIN SIMM**

±0.13 (±0.005) TOLERANCE UNLESS OTHERWISE SPECIFIED
ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES

PACKAGE DIMENSION: 80-PIN SIMM, LOW PROFILE

±0.13 (±0.005) TOLERANCE UNLESS OTHERWISE SPECIFIED
ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES

**ORDERING INFORMATION****W P F 1M32 X - 90 X C 5 X****LEAD FINISH:**

T = Tin Edge Connectors

Blank = Gold Edge Connectors

V_{PP} PROGRAMMING VOLTAGE

5 = 5V

DEVICE GRADE:

C = Commercial

0 to + 70°C

PACKAGE TYPE:

PS = 80 pin Plastic SIMM

LS = 80 pin Plastic SIMM, Low Profile*

ACCESS TIME (ns)**RESET OPTIONS:**V = $\overline{\text{RESET}}$ tied to VccR = $\overline{\text{RESET}}$ tied to Pin 7 for system control of resetP = $\overline{\text{RESET}}$ tied to power supervisor circuit

On-board active Reset control

ORGANIZATION, 1M x 32**Flash PROM****Plastic Module****WHITE MICROELECTRONICS*** *Package to be developed.*